

December 2000

QFET™

FQD4P25 / FQU4P25

250V P-Channel MOSFET

General Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

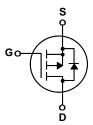
This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand a high energy pulse in the avalanche and commutation modes. These devices are well suited for high efficiency switching DC/DC converters.

Features

- -3.1A, -250V, $R_{DS(on)} = 2.1\Omega @V_{GS} = -10 V$
- Low gate charge (typical 10 nC)
- Low Crss (typical 10.3 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability







Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD4P25 / FQU4P25	Units
V _{DSS}	Drain-Source Voltage		-250	V
I _D	Drain Current - Continuous (T _C = 25°	C)	-3.1	А
	- Continuous (T _C = 100)°C)	-1.96	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	-12.4	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	280	mJ
I _{AR}	Avalanche Current	(Note 1)	-3.1	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-5.5	V/ns
P_{D}	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		45	W
	- Derate above 25°C		0.36	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.78	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-250			V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	I_D = -250 μA, Referenced to 25°C		-0.21		V/°C
I _{DSS}	Zara Oata Valla va Basis Oassat	V _{DS} = -250 V, V _{GS} = 0 V			-1	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = -200 V, T _C = 125°C			-10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0		-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -1.55 A		1.63	2.1	Ω
9 _{FS}	Forward Transconductance	V _{DS} = -40 V, I _D = -1.55 A (Note 4)		2.0		S
C _{oss}	Output Capacitance Reverse Transfer Capacitance	f = 1.0 MHz		65 10	85 13	pF pF
C _{rss}	Reverse Transfer Capacitance			10	13	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = -125 V, I _D = -4.0 A,		9.5	30	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		60	130	ns
t _{d(off)}	Turn-Off Delay Time			14	40	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		27	65	ns
Qg	Total Gate Charge	$V_{DS} = -200 \text{ V}, I_{D} = -4.0 \text{ A},$		10.3	14	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -10 V		2.7		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		5.2		nC
Drain-9	Source Diode Characteristics a	nd Maximum Ratings				
l _S	Maximum Continuous Drain-Source Diode Forward Current				-3.1	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				-12.4	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -3.1 \text{ A}$			-5.0	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = -4.0 A,		140		ns

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 46.6mH, I_{AS} = -3.1A, V_{DD} = -50V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} ≤ -4.0A, di/dt ≤ 300A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

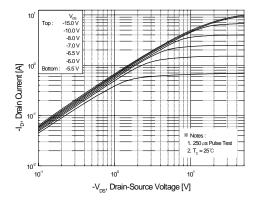


Figure 1. On-Region Characteristics

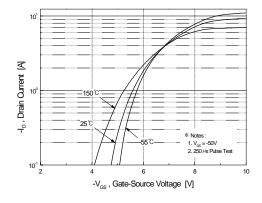


Figure 2. Transfer Characteristics

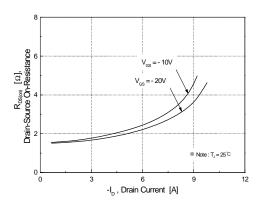


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

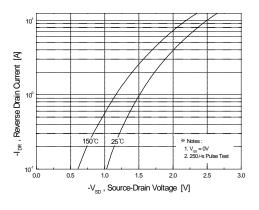


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

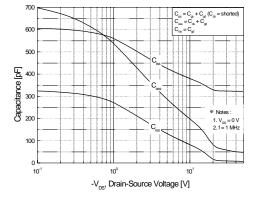


Figure 5. Capacitance Characteristics

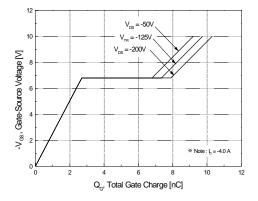
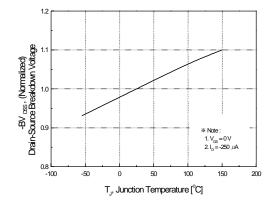


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)



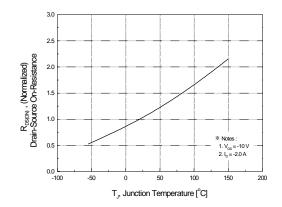
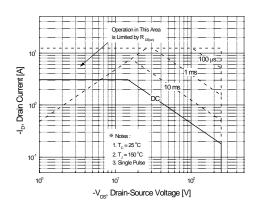


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



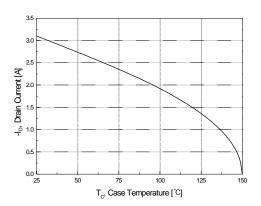


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

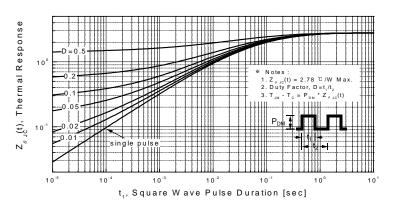
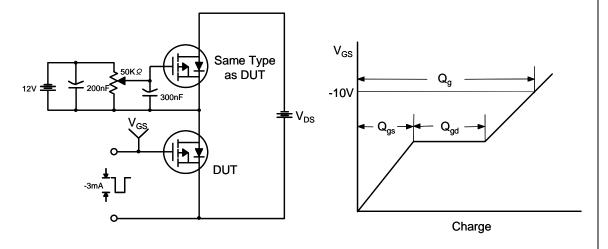


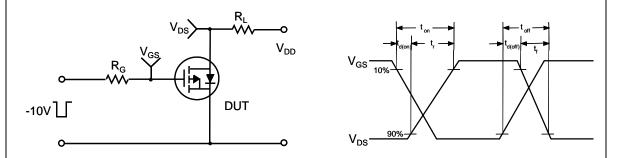
Figure 11. Transient Thermal Response Curve

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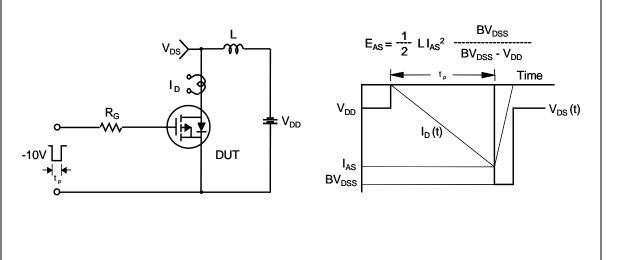
Gate Charge Test Circuit & Waveform



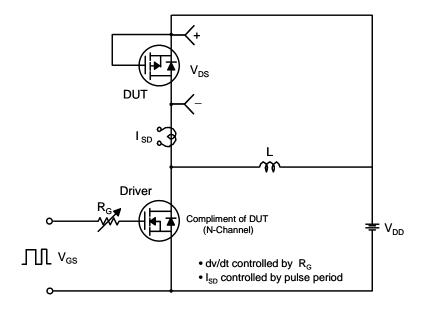
Resistive Switching Test Circuit & Waveforms

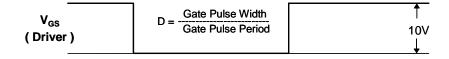


Unclamped Inductive Switching Test Circuit & Waveforms



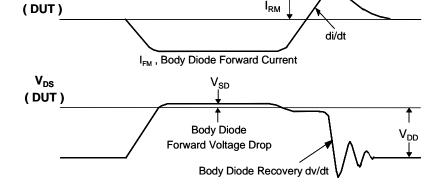
Peak Diode Recovery dv/dt Test Circuit & Waveforms



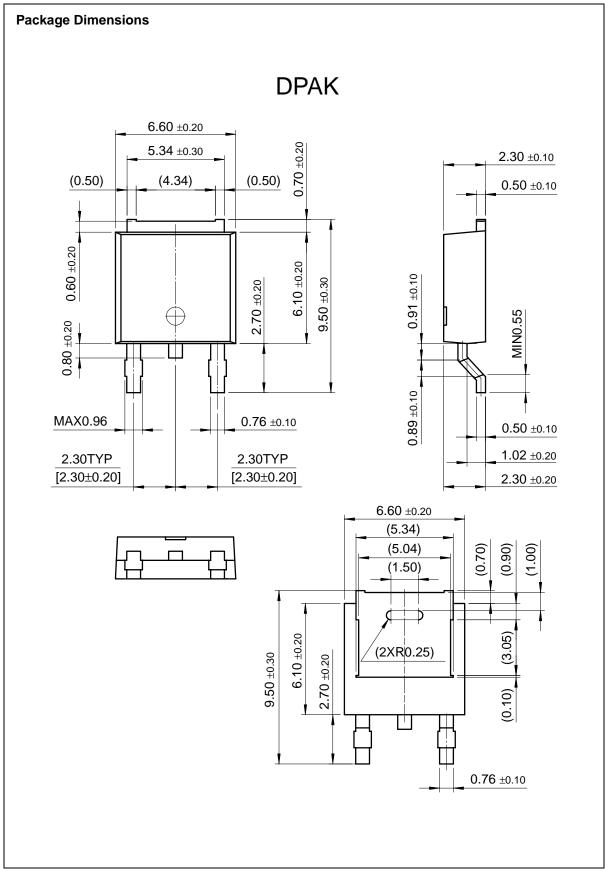


I_{SD}

Body Diode Reverse Current

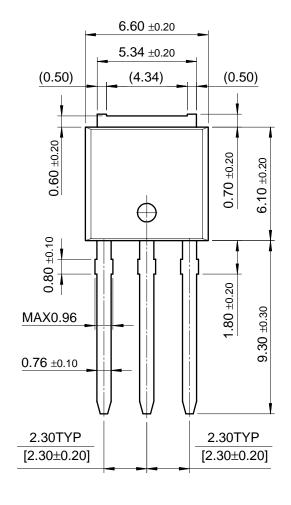


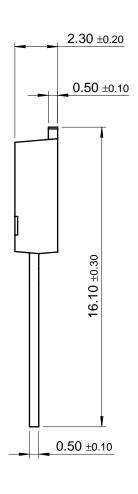
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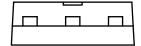




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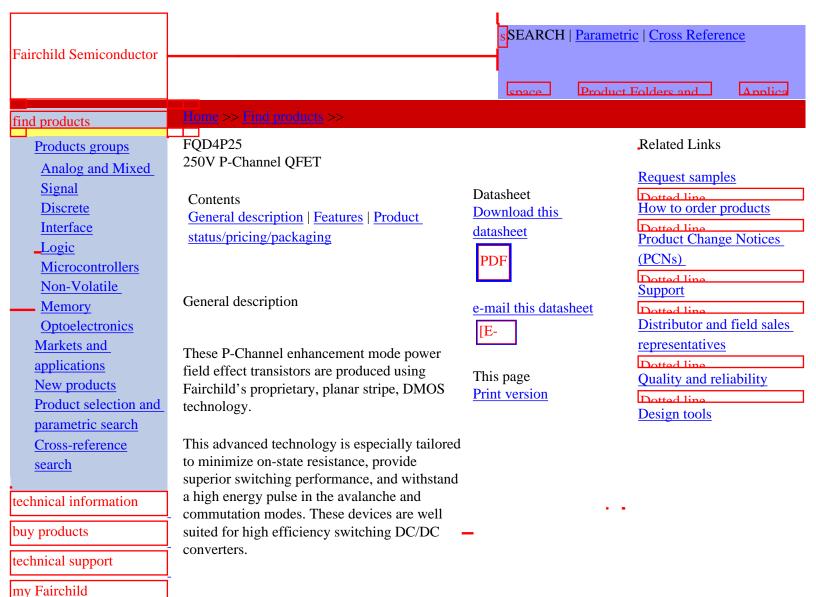
 VCX^{TM}

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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Features

company

- -3.1A, -250V, $R_{DS(on)} = 2.1\Omega$ @ $V_{GS} = -10V$
- Low gate charge (typical 10nC)
- Low Crss (typical 10.3pF)
- Fast switching
- 100% avalanche tested

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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method
FQD4P25TF	Full Production	\$0.474	TO-252(DPAK)	2	TAPE REEL
FQD4P25TM	Full Production	\$0.474	TO-252(DPAK)	2	TAPE REEL

* 1,000 piece Budgetary Pricing

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